

DCR4500A42



Phase Control Thyristor

Preliminary Information

DS5942-1.0 June 2009 (LN 26810)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- High Power Drives
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V _{DRM} and V _{RRM} V	Conditions
DCR4500A42* DCR4500A40 DCR4500A36	4200 4000 3600	$\begin{array}{l} T_{vj} = -40 \ \mbox{°C} \ to \ 125 \ \mbox{°C}, \\ I_{DRM} = I_{RRM} = 300 \ \mbox{MA}, \\ V_{DRM}, \ V_{RRM} \ t_p = 10 \ \mbox{ms}, \\ V_{DSM} \& \ V_{RSM} = \\ V_{DRM} \& \ V_{RRM} \ + 100 \ \ \ respectively \end{array}$

Lower voltage grades available. *4100V @ -40°C, 4200V @ 0°C

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR4500A42

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

KEY PARAMETERS

4200V
4500A
60800A
2000V/µs
200A/μs

* Higher dV/dt selections available

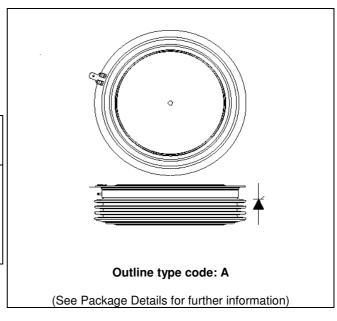


Fig. 1 Package outline



CURRENT RATINGS

 T_{case} = 60 °C unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Si	de Cooled			
I _{T(AV)}	Mean on-state current	Half wave resistive load	4500	А
I _{T(RMS)}	RMS value	-	7068	А
Ι _Τ	Continuous (direct) on-state current	-	6330	А

SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I _{TSM}	Surge (non-repetitive) on-state current	10ms half sine, T _{case} = 125 °C	60.8	kA
l ² t	I ² t for fusing	V _R = 0	18.48	MA ² s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Condition	Min.	Max.	Units	
R _{th(j-c)}	Thermal resistance – junction to case	Double side cooled	Double side cooled DC		0.00603	℃/W
		Single side cooled	ingle side cooled Anode DC		0.01024	℃/W
			Cathode DC	-	0.01467	°C/W
R _{th(c-h)}	Thermal resistance – case to heatsink	Clamping force 83.0kNDouble side(with mounting compound)Single side		-	0.001	°C/W
				-	0.002	°C/W
T_{vj}	Virtual junction temperature	On-state (conducting)		-	135	°C
		Reverse (blocking)		-	125	°C
T _{stg}	Storage temperature range			-55	125	°C
Fm	Clamping force		74.0	91.0	kN	

DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions			Max.	Units
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125 ℃		-	300	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125℃, ga	ate open	-	2000	V/µs
dl/dt	Rate of rise of on-state current	From 67% V_{DRM} to 2x $I_{\text{T}(\text{AV})}$	Repetitive 50Hz	-	200	A/µs
		Gate source 30V, 10Ω, t _r < 0.5μs, T _j = 125 ℃			500	A/µs
$V_{T(TO)}$	Threshold voltage – Low level	500 to 2200A at T _{case} = 125°	C	-	0.75	V
	Threshold voltage – High level	2200 to 8000A at T _{case} = 125	S℃	-	0.92	V
r _T	On-state slope resistance – Low level	500A to 2200A at $T_{case} = 125$	-	0.205	mΩ	
	On-state slope resistance – High level	2200A to 8000A at T _{case} = 125 °C			0.122	mΩ
t _{gd}	Delay time	$V_D = 67\% V_{DRM}$, gate source 30V, 10 Ω t _r = 0.5µs, T _j = 25 °C			3	μs
tq	Turn-off time	$\begin{split} &I_T = 5000A, \ T_j = 125^\circ\!\!C, \\ &V_R = 200V, \ dI/dt = 5A/\mu s, \\ &dV_{DR}/dt = 20V/\mu s \ linear \end{split}$		900	μs	
Qs	Stored charge	I _T = 3000A, Τ _i = 125 °C, dl/dt – 1A/μs,		2920	4875	μC
I _{RR}	Reverse recovery current	$V_{Rpeak} \sim 2500V, V_R \sim 1700V$	42	57	A	
۱L	Latching current	$T_j = 25 ^{\circ}C, V_D = 5V$	-	3	A	
lμ	Holding current	$T_j = 25 ^{\circ}C, R_{G-K} = \infty, I_{TM} = 500$	-	300	mA	



GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V _{GT}	Gate trigger voltage	$V_{DRM} = 5V, T_{case} = 25 ^{\circ}C$	1.5	۷
V_{GD}	Gate non-trigger voltage	At 50% V _{DRM,} T _{case} = 125 ℃	0.4	۷
I _{GT}	Gate trigger current	$V_{DRM} = 5V, T_{case} = 25 ^{\circ}C$	300	mA
I _{GD}	Gate non-trigger current	At 50% V _{DRM,} T _{case} = 125℃	10	mA

CURVES

) ***Nex SEMICONDUCTOR

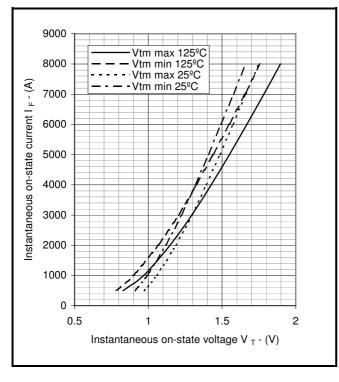
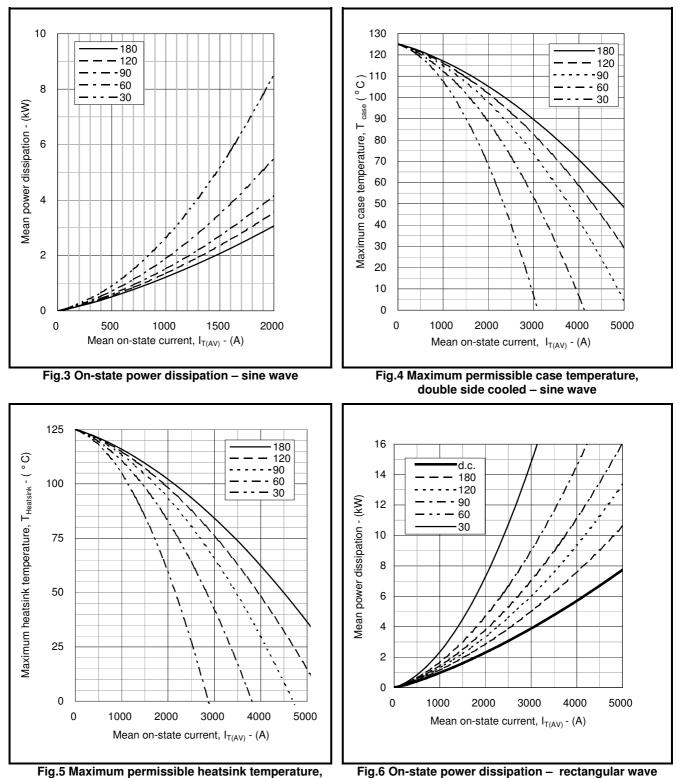


Fig.2 Maximum & minimum on-state characteristics

V_{TM} EQUATION

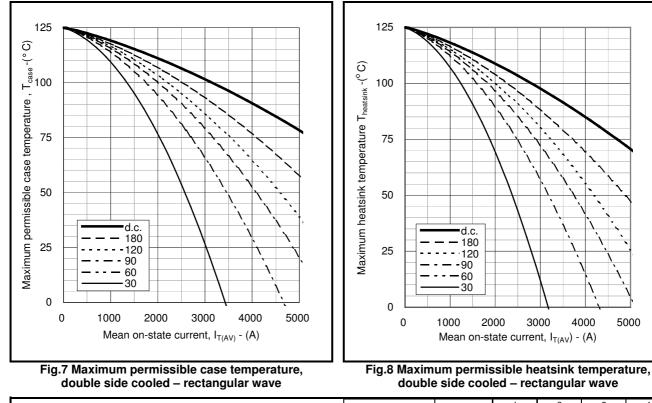
Where A = -0.208640 B = 0.171688 $V_{TM} = A + Bln (I_T) + C.I_T + D.\sqrt{I_T}$ C = 0.000113D = 0.003842these values are valid for T_{i} = 125 $^{\circ}\!\!\mathrm{C}$ for I_{T} 500A to 8000A

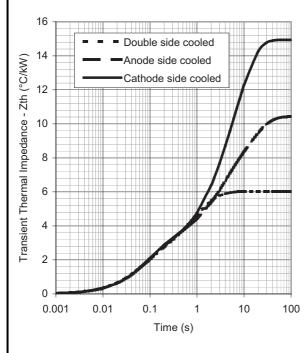


double side cooled - sine wave



© Z Tion Implant





4 R_i (℃/kW) 3.01541 1.048955 0.983519 0.983519 Double side cooled 0.703874 1.904794 T_i (s) 0.059 0.059 R_i (℃/kW) 3.156003 4.092806 1.556555 1.623962 Anode side cooled T_i (s) 2.69023 13.79162 0.059 0.205916 R_i (℃/kW) 7.077369 3.483481 1.745839 2.634274 Cathode side cooled 6.648601 8.436484 1.762119 0.08069 T_i (s)

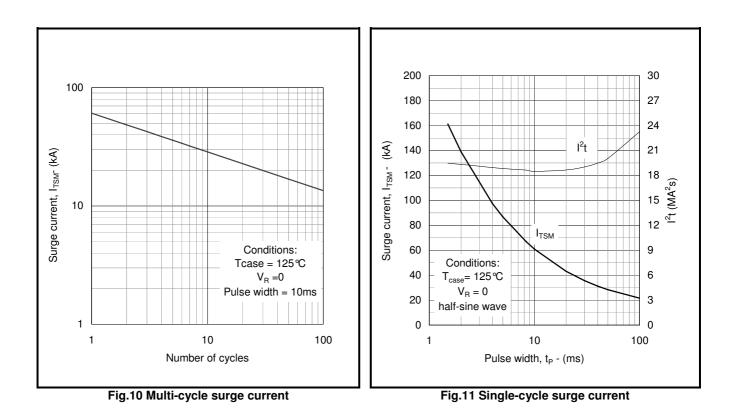
$$Z_{th} = \sum_{i=1}^{i=4} [R_i \times (1 - \exp(T/T_i))]$$

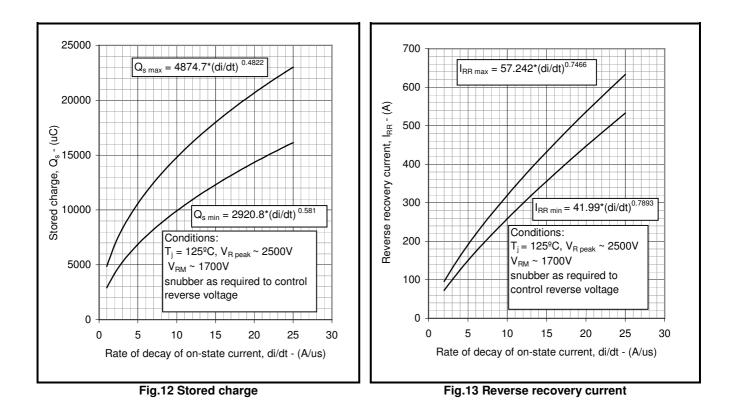
$\Delta \textbf{R}_{\text{th(j-c)}} \text{ Conduction}$

Tables show the increments of thermal resistance $R_{th(j-c)}$ when the device operates at conduction angles other than d.c.

C	Double side cooling			Anode Side Cooling				Cathode Sided Cooling			
	$\Delta Z_{th}(z)$			$\Delta Z_{th}(z)$				ΔZ	_{th} (z)		
θ°	sine.	rect.		θ°	sine.	rect.		θ°	sine.	rect.	
180	0.44	0.31		180	0.42	0.30		180	0.42	0.30	
120	0.49	0.43		120	0.47	0.41		120	0.47	0.41	
90	0.55	0.49		90	0.52	0.46		90	0.52	0.46	
60	0.60	0.55		60	0.57	0.52		60	0.57	0.52	
30	0.64	0.61		30	0.61	0.58		30	0.60	0.58	
15	0.66	0.64		15	0.62	0.61		15	0.62	0.60	

Fig.9 Maximum (limit) transient thermal impedance – junction to case (°C/kW)





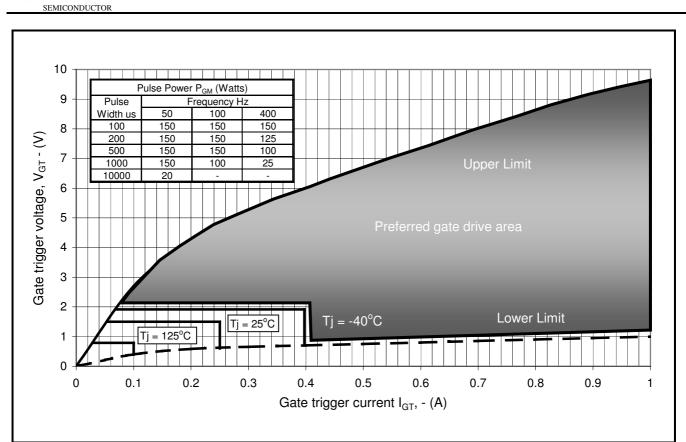


Fig14 Gate Characteristics

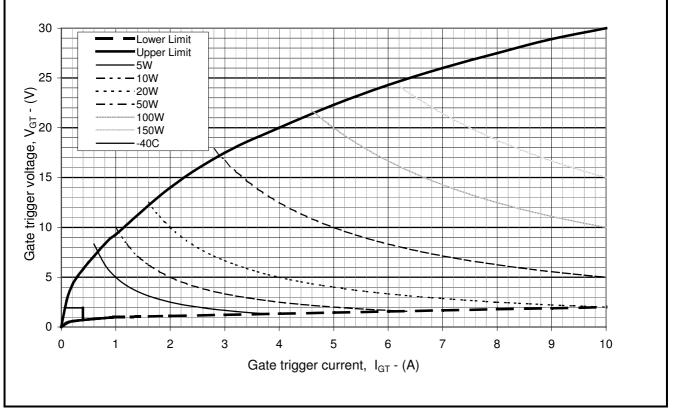


Fig. 15 Gate characteristics

©2 Ion Implant

DCR4500A42

C BYNCX

PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

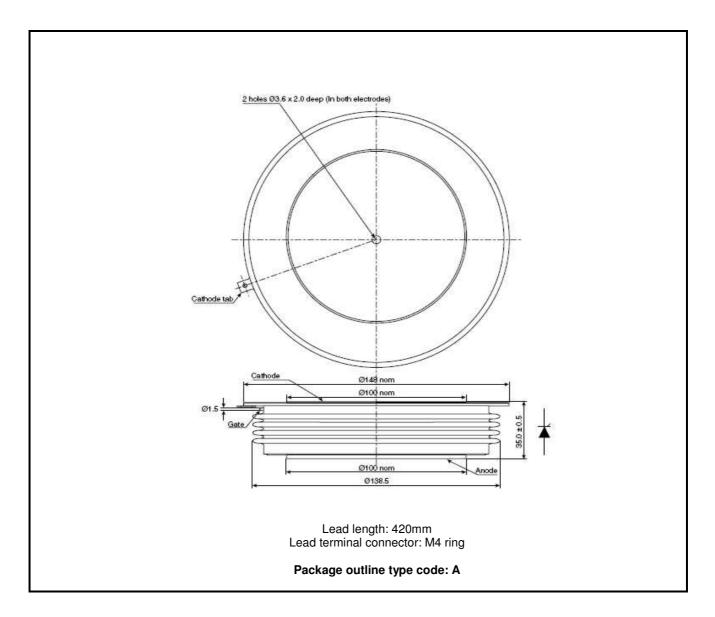


Fig.16 Package outline



POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



http://www.dynexsemi.com

e-mail: power_solutions@dynexsemi.com

HEADQUARTERS OPERATIONS DYNEX SEMICONDUCTOR LTD

Doddington Road, Lincoln Lincolnshire, LN6 3LF. United Kingdom. Tel: +44(0)1522 500500 Fax: +44(0)1522 500550 CUSTOMER SERVICE Tel: +44(0)1522 502753 / 502901. Fax: +44(0)1522 500020

© Dynex Semiconductor 2003 TECHNICAL DOCUMENTATION – NOT FOR RESALE. PRODUCED IN UNITED KINGDOM.

This publication is issued to provide information only which (unless agreed by the Company in writing) may not be used, applied or reproduced for any purpose nor form part of any order or contract nor to be regarded as a representation relating to the products or services concerned. No warranty or guarantee express or implied is made regarding the capability, performance or suitability of any product or service. The Company reserves the right to alter without prior notice the specification, design or price of any product or service. Information concerning possible methods of use is provided as a guide only and does not constitute any guarantee that such methods of use will be satisfactory in a specific piece of equipment. It is the user's responsibility to fully determine the performance and suitability of any equipment using such information and to ensure that any publication or data used is up to date and has not been superseded. These products are not suitable for use in any medical products whose failure to perform may result in significant injury or death to the user. All products and materials are sold and services provided subject to the Company's conditions of sale, which are available on request.

All brand names and product names used in this publication are trademarks, registered trademarks or trade names of their respective owners.